



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named
Inventor : David W. Duquette

Appln. No. : 09/767,199

Filed : January 22, 2001

For : IMPROVED LASER ALIGN SENSOR
WITH SEQUENCING LIGHT
SOURCES

Docket No.: C34.12-0021

Group Art Unit: 2877

Examiner:

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Washington, D.C. 20231

I HEREBY CERTIFY THAT THIS PAPER IS BEING
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WASHINGTON, D.C. 20231, THIS

DAY OF May, 2001


PATENT ATTORNEY

Sir:

The patents or publications listed on the enclosed PTO
Form-1449 are submitted pursuant to 37 C.F.R. § 1.97. Copies of
the patents or publications cited are enclosed.

The Director is authorized to charge any fee deficiency
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Account No. 23-1123.


Respectfully submitted,

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FORM PTO-1449	Atty. Docket No.: C34.12-0021	Appl. No.: 09/767,199
<p>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</p> 	First Named Inventor:	
	David W. Duquette	
	Filing Date	Group Art:
	January 22, 2001	2877

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
AA	5,467,186	11/14/95	Indo et al.	356	150	
AB	5,570,993	11/05/96	Onodera et al.	414	783	
AC	5,741,114	04/21/98	Onodera	414	783	
AD	5,749,142	05/12/98	Hanamura	29	833	
AE						
AF						
AG						
AH						
AI						
AJ						

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
AK	6-21697	01/28/94	Japan			(Abstract Only)
AL	9-293998	04/26/96	Japan			X
AM						
AN						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AQ	
AR	
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EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.